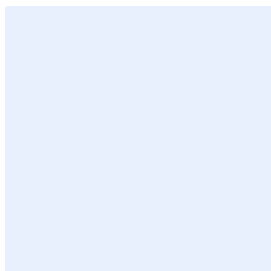


Prüfbericht-Nr.: <i>Test report no.:</i>	IN24B1UR 001	Auftrags-Nr.: <i>Order no.:</i>	146886139 010	Seite 1 von 3 Page 1 of 3	
Kunden-Referenz-Nr.: <i>Client reference no.:</i>	2133653	Auftragsdatum: <i>Order date:</i>	2024-02-22		
Auftraggeber: <i>Client:</i>	KoreLock, Inc 7100 E. Bellevue Ave. Suite 203, Greenwood Village, CO, USA, 80111				
Prüfgegenstand: <i>Test item:</i>	KeyInCode 5200 Series Smart Lock				
Bezeichnung <i>Identification</i>	5200	Serien -Nr.: <i>Serial no.:</i>	Engineering Samples		
Auftrags-Inhalt: <i>Order content:</i>	Testing and issue of Test Report with Grant Certificate				
Prüfgrundlage: <i>Test specification:</i>	FCC 1.1310 KDB 447498 D01				
Wareneingangsdatum: <i>Date of sample receipt:</i>	2024-02-22				
Prüfmuster-Nr.: <i>Test sample no:</i>	A003662523-001 & A003662523-002				
Prüfzeitraum: <i>Testing period:</i>	2024-02-26 - 2024-03-11				
Ort der Prüfung: <i>Place of testing:</i>	Wireless laboratory, Bangalore				
Prüflaboratorium: <i>Testing laboratory:</i>	TÜV Rheinland (India) Pvt. Ltd. 27/B,2nd cross road, Electronic city Phase1, Bangalore-560100, India FCC Test Site Registration No: 496599 IC Test Site Registration No: 27711				
Prüfergebnis*: <i>Test result*:</i>	Pass				
geprüft von: <i>tested by:</i>	genehmigt von: <i>authorized by:</i>				
Datum: <i>Date:</i> 2024-05-07	Ausstellatum: <i>Issue date:</i> 2024-05-07				
Stellung / Position:	M.V.Naveen Kumar Senior Engineer	Stellung / Position:	Madhu K.N Assistant Manager		
Sonstiges / Other:	FCC ID: 2BBNS-KL5200				
Zustand des Prüfgegenstandes bei Anlieferung: <i>Condition of the test item at delivery:</i>	Prüfmuster vollständig und unbeschädigt <i>Test item complete and undamaged</i>				
* Legende:	1 = sehr gut P(ass) = entspricht o.g. Prüfgrundlage(n)	2 = gut F(ail) = entspricht nicht o.g. Prüfgrundlage(n)	3 = befriedigend F(ail) = entspricht nicht o.g. Prüfgrundlage(n)	4 = ausreichend N/A = nicht anwendbar	5 = mangelhaft N/T = nicht getestet
* Legend:	1 = very good P(ass) = passed a.m. test specification(s)	2 = good F(ail) = failed a.m. test specification(s)	3 = satisfactory F(ail) = failed a.m. test specification(s)	4 = sufficient N/A = not applicable	5 = poor N/T = not tested
Dieser Prüfbericht bezieht sich nur auf das o.g. Prüfmuster und darf ohne Genehmigung der Prüfstelle nicht auszugsweise vervielfältigt werden. Dieser Bericht berechtigt nicht zur Verwendung eines Prüfzeichens. <i>This test report only relates to the a. m. test sample. Without permission of the test center this test report is not permitted to be duplicated in extracts. This test report does not entitle to carry any test mark.</i>					

RF Exposure Report

Following FCC KDB 447498 D01 General SAR test exclusion guidelines

The corresponding SAR exclusion threshold condition, listed below:

1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation Distances ≤ 50 mm are determined by: $[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] * [\sqrt{f} \text{ (GHz)}] \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g.

Extremity SAR, where

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation.
- The result is rounded to one decimal place for comparison The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm according to 5) in section 4.1 is applied to determine SAR test exclusion(447498 D01 General RF Exposure Guidance v06)

2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following

- $[\text{Power allowed at numeric threshold for 50 mm in step 1}) + (\text{test separation distance} - 50 \text{ mm}) \cdot (f(\text{MHz})/150)] \text{ mW}$, at 100 MHz to 1500 MHz
- $[\text{Power allowed at numeric threshold for 50 mm in step 1}) + (\text{test separation distance} - 50 \text{ mm}) \cdot 10] \text{ mW}$ at > 1500 MHz and ≤ 6 GHz

3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion,

- The power threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by $[1 + \log(100/f(\text{MHz}))]$ for *test separation distances* > 50 mm and < 200 mm
- The power threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by $\frac{1}{2}$ for *test separation distances* ≤ 50 mm
- SAR measurement procedures are not established below 100 MHz When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.

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Test Report No.:

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SAR Test Exclusion Thresholds

Maximum Measured Transmitter Power:

Radio Protocol	Frequency (GHz)	Max. Power Including Tune-up Tolerance (dBm)	Max. Power Including Tune-up Tolerance (mW)	Min. Test Separation distance (mm)	SAR Test Exclusion Calculation Values (mW)	SAR Test exclusion Thresholds (mW)
Wi-Fi 2.4GHz	2.412	19.03	79.9834	150	1079.983	1097
BLE	2.440	8.40	6.9183	150	1006.918	1096

Simultaneous Operation:

Radio Protocol	Frequency (GHz)	Max. Power Including Tune-up Tolerance (mW)	Min. Test Separation distance (mm)	SAR Test Exclusion Calculation Values (mW)	SAR Test exclusion Thresholds (mW)
Wi-Fi 2.4GHz + BLE	2.412 & 2.440	86.9017	150	1086.90	1096

Hence, the EUT is exempted from routine SAR evaluation.

Note:

1. Calculate SAR exclusion threshold from condition 2 with condition 150mm.
2. Client declared as tune up tolerance 1dB